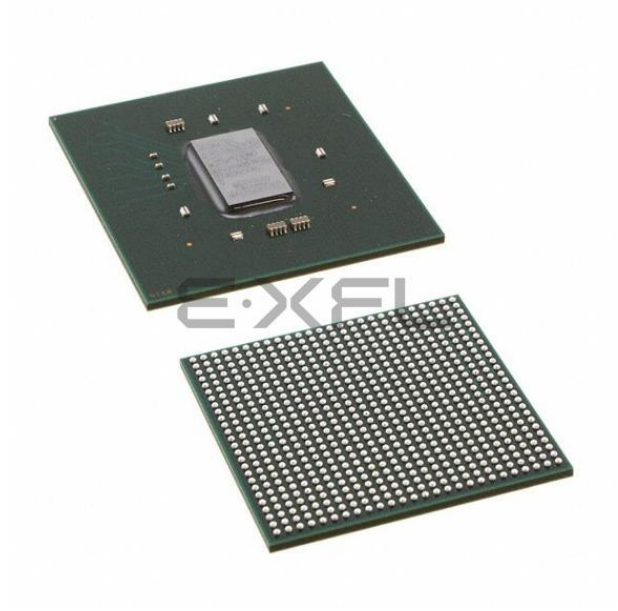
AMD Xilinx - XC7K410T-3FFG676E Datasheet



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Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	31775
Number of Logic Elements/Cells	406720
Total RAM Bits	29306880
Number of I/O	400
Number of Gates	-
Voltage - Supply	0.97V ~ 1.03V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 100°C (TJ)
Package / Case	676-BBGA, FCBGA
Supplier Device Package	676-FCBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7k410t-3ffg676e

Table 7 shows the minimum current, in addition to I_{CCQ}, that are required by Kintex-7 devices for proper power-on and configuration. If the current minimums shown in Table 6 and Table 7 are met, the device powers on after all five supplies have passed through their power-on reset threshold voltages. The FPGA must not be configured until after V_{CCINT} is applied.

Once initialized and configured, use the XPower tools to estimate current drain on these supplies.

Table 7: **Power-On Current for Kintex-7 Devices**

Device	$I_{CCINTMIN}$	$I_{CCAUXMIN}$	I_{CCOMIN}	I_{CCAUX_IOMIN}	$I_{CCBRAMMIN}$	Units
	Typ(1)	Typ(1)	Typ(1)	Typ(1)	Typ(1)	
XC7K70T	I_{CCINTQ} + 450	I_{CCAUXQ} + 40	I_{CCOQ} + 40 mA per bank	$I_{CCOAUXIOQ}$ + 40 mA per bank	$I_{CCBRAMQ}$ + 40	mA
XC7K160T	I_{CCINTQ} + 550	I_{CCAUXQ} + 50	I_{CCOQ} + 40 mA per bank	$I_{CCOAUXIOQ}$ + 40 mA per bank	$I_{CCBRAMQ}$ + 40	mA
XC7K325T	I_{CCINTQ} + 600	I_{CCAUXQ} + 80	I_{CCOQ} + 40 mA per bank	$I_{CCOAUXIOQ}$ + 40 mA per bank	$I_{CCBRAMQ}$ + 40	mA
XC7K355T	I_{CCINTQ} + 1450	I_{CCAUXQ} + 109	I_{CCOQ} + 40 mA per bank	$I_{CCOAUXIOQ}$ + 40 mA per bank	$I_{CCBRAMQ}$ + 81	mA
XC7K410T	I_{CCINTQ} + 1500	I_{CCAUXQ} + 125	I_{CCOQ} + 40 mA per bank	$I_{CCOAUXIOQ}$ + 40 mA per bank	$I_{CCBRAMQ}$ + 90	mA
XC7K420T	I_{CCINTQ} + 2200	I_{CCAUXQ} + 180	I_{CCOQ} + 40 mA per bank	$I_{CCOAUXIOQ}$ + 40 mA per bank	$I_{CCBRAMQ}$ + 108	mA
XC7K480T	I_{CCINTQ} + 2200	I_{CCAUXQ} + 180	I_{CCOQ} + 40 mA per bank	$I_{CCOAUXIOQ}$ + 40 mA per bank	$I_{CCBRAMQ}$ + 108	mA

Notes:

1. Typical values are specified at nominal voltage, 25°C.
2. Use the XPower Estimator (XPE) spreadsheet tool (download at http://www.xilinx.com/power) to calculate maximum power-on currents.

Table 8: **Power Supply Ramp Time**

Symbol	Description	Conditions	Min	Max	Units
T_{VCCINT}	Ramp time from GND to 90% of V_{CCINT}		0.2	50	ms
T_{VCCO}	Ramp time from GND to 90% of V_{CCO}		0.2	50	ms
T_{VCCAUX}	Ramp time from GND to 90% of V_{CCAUX}		0.2	50	ms
T_{VCCAUX_IO}	Ramp time from GND to 90% of V_{CCAUX_IO}		0.2	50	ms
$T_{VCCBRAM}$	Ramp time from GND to 90% of V_{CCBRAM}		0.2	50	ms
$T_{VCCO2VCCAUX}$	Allowed time per power cycle for $V_{CCO} - V_{CCAUX} > 2.625V$	T_J = 100°C(1)	–	500	ms
		T_J = 85°C(1)	–	800	
$T_{MGTAVCC}$	Ramp time from GND to 90% of $V_{MGTAVCC}$		0.2	50	ms
$T_{MGTAVTT}$	Ramp time from GND to 90% of $V_{MGTAVTT}$		0.2	50	ms
$T_{MGTVCCAUX}$	Ramp time from GND to 90% of $V_{MGTVCCAUX}$		0.2	50	ms

Notes:

1. Based on 240,000 power cycles with nominal V_{CCO} of 3.3V or 36,500 power cycles with a worst case V_{CCO} of 3.465V.

Table 10: **Differential SelectIO DC Input and Output Levels**

I/O Standard	V_{ICM}[1]			V_{ID}[2]			V_{OCM}[3]			V_{OD}[4]		
	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max
BLVDS_25	0.300	1.200	1.425	0.100	–	–	–	1.250	–	Note 5		
MINI_LVDS_25	0.300	1.200	V_{CCAUX}	0.200	0.400	0.600	1.000	1.200	1.400	0.300	0.450	0.600
PPDS_25	0.200	0.900	V_{CCAUX}	0.100	0.250	0.400	0.500	0.950	1.400	0.100	0.250	0.400
RSDS_25	0.300	0.900	1.500	0.100	0.350	0.600	1.000	1.200	1.400	0.100	0.350	0.600
TMDS_33	2.700	2.965	3.230	0.150	0.675	1.200	V_{CCO}–0.405	V_{CCO}–0.300	V_{CCO}–0.190	0.400	0.600	0.800

Notes:

1. V_{ICM} is the input common mode voltage.
2. V_{ID} is the input differential voltage (Q – $\overline{Q}$).
3. V_{OCM} is the output common mode voltage.
4. V_{OD} is the output differential voltage (Q – $\overline{Q}$).
5. V_{OD} for BLVDS will vary significantly depending on topology and loading.
6. LVDS_25 is specified in Table 12.
7. LVDS is specified in Table 13.

Table 11: **Complementary Differential SelectIO DC Input and Output Levels**

I/O Standard	V_{ICM}[1]			V_{ID}[2]		V_{OL}[3]	V_{OH}[4]	I_{OL}	I_{OH}
	V, Min	V, Typ	V, Max	V, Min	V, Max	V, Max	V, Min	mA, Max	mA, Min
DIFF_HSTL_I	0.300	0.750	1.125	0.100	–	0.400	V_{CCO}–0.400	8.00	–8.00
DIFF_HSTL_I_18	0.300	0.900	1.425	0.100	–	0.400	V_{CCO}–0.400	8.00	–8.00
DIFF_HSTL_II	0.300	0.750	1.125	0.100	–	0.400	V_{CCO}–0.400	16.00	–16.00
DIFF_HSTL_II_18	0.300	0.900	1.425	0.100	–	0.400	V_{CCO}–0.400	16.00	–16.00
DIFF_HSUL_12	0.300	0.600	0.850	0.100	–	20% V_{CCO}	80% V_{CCO}	0.100	–0.100
DIFF_MOBILE_DDR	0.300	0.900	1.425	0.100	–	10% V_{CCO}	90% V_{CCO}	0.100	–0.100
DIFF_SSTL12	0.300	0.600	0.850	0.100	–	(V_{CCO}/2) – 0.150	(V_{CCO}/2) + 0.150	14.25	–14.25
DIFF_SSTL135	0.300	0.675	1.000	0.100	–	(V_{CCO}/2) – 0.150	(V_{CCO}/2) + 0.150	13.0	–13.0
DIFF_SSTL135_R	0.300	0.675	1.000	0.100	–	(V_{CCO}/2) – 0.150	(V_{CCO}/2) + 0.150	8.9	–8.9
DIFF_SSTL15	0.300	0.750	1.125	0.100	–	(V_{CCO}/2) – 0.175	(V_{CCO}/2) + 0.175	13.0	–13.0
DIFF_SSTL15_R	0.300	0.750	1.125	0.100	–	(V_{CCO}/2) – 0.175	(V_{CCO}/2) + 0.175	8.9	–8.9
DIFF_SSTL18_I	0.300	0.900	1.425	0.100	–	(V_{CCO}/2) – 0.470	(V_{CCO}/2) + 0.470	8.00	–8.00
DIFF_SSTL18_II	0.300	0.900	1.425	0.100	–	(V_{CCO}/2) – 0.600	(V_{CCO}/2) + 0.600	13.4	–13.4

Notes:

1. V_{ICM} is the input common mode voltage.
2. V_{ID} is the input differential voltage (Q – $\overline{Q}$).
3. V_{OL} is the single-ended low-output voltage.
4. V_{OH} is the single-ended high-output voltage.

LVDS DC Specifications (LVDS_25)

The LVDS_25 standard is available in the HR I/O banks. See UG471: *7 Series FPGAs SelectIO Resources User Guide* for more information.

Table 12: **LVDS_25 DC Specifications**

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.375	2.500	2.625	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	R_T = 100 Ω across Q and $\overline{Q}$ signals	–	–	1.675	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	R_T = 100 Ω across Q and $\overline{Q}$ signals	0.700	–	–	V
V_{ODIFF}	Differential Output Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	R_T = 100 Ω across Q and $\overline{Q}$ signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage	R_T = 100 Ω across Q and $\overline{Q}$ signals	1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High		100	350	600	mV
V_{ICM}	Input Common-Mode Voltage		0.300	1.200	1.425	V

LVDS DC Specifications (LVDS)

The LVDS standard is available in the HP I/O banks. See UG471: *7 Series FPGAs SelectIO Resources User Guide* for more information.

Table 13: **LVDS DC Specifications**

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		1.710	1.800	1.890	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	R_T = 100 Ω across Q and $\overline{Q}$ signals	–	–	1.675	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	R_T = 100 Ω across Q and $\overline{Q}$ signals	0.825	–	–	V
V_{ODIFF}	Differential Output Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	R_T = 100 Ω across Q and $\overline{Q}$ signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage	R_T = 100 Ω across Q and $\overline{Q}$ signals	1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	Common-mode input voltage = 1.25V	100	350	600	mV
V_{ICM}	Input Common-Mode Voltage	Differential input voltage = ±350 mV	0.300	1.200	1.425	V

Table 17: **Maximum Physical Interface (PHY) Rate for Memory Interfaces (FFG Packages)(1)(2)**

Memory Standard	I/O Bank Type	V_{CCAUX_IO}	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
4:1 Memory Controllers							
DDR3	HP	2.0V	1866	1866	1600	1333	Mb/s
	HP	1.8V	1600	1333	1066	1066	Mb/s
	HR	N/A	1066	1066	800	800	Mb/s
DDR3L	HP	2.0V	1600	1600	1333	1066	Mb/s
	HP	1.8V	1333	1066	800	800	Mb/s
	HR	N/A	800	800	667	667	Mb/s
DDR2	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V	800	800	800	800	Mb/s
	HR	N/A	800	800	800	800	Mb/s
RLDRAM III(3)	HP	2.0V	800	667	667	533	MHz
	HP	1.8V	550	500	450	450	MHz
	HR	N/A	N/A				
2:1 Memory Controllers							
DDR3	HP	2.0V	1066	1066	800	800	Mb/s
	HP	1.8V	1066	1066	800	800	Mb/s
	HR	N/A	1066	1066	800	800	Mb/s
DDR3L	HP	2.0V	1066	1066	800	800	Mb/s
	HP	1.8V	1066	1066	800	800	Mb/s
	HR	N/A	800	800	667	667	Mb/s
DDR2	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V					
	HR	N/A					
QDR II+(4)	HP	2.0V	550	500	450	450	MHz
	HP	1.8V					
	HR	N/A	500	450	400	400	MHz
RLDRAM II	HP	2.0V	533	500	450	450	MHz
	HP	1.8V					
	HR	N/A					
LPDDR2(3)	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V	800	800	800	800	Mb/s
	HR	N/A	800	667	667	667	Mb/s

Notes:

1. V_{REF} tracking is required. For more information, see UG586, *7 Series FPGAs Memory Interface Solutions User Guide*.
2. When using the internal V_{REF}, the maximum data rate is 800 Mb/s (400 MHz).
3. RLDRAM III (BL = 4, BL = 8) and LPDDR2 specifications have not been validated with memory IP.
4. The maximum QDRII+ performance specifications are for burst-length 4 (BL = 4) implementations. Burst length 2 (BL = 2) implementations are limited to 333 MHz for all speed grades and I/O bank types.

Table 20: **1.8V IOB High Performance (HP) Switching Characteristics *(Cont'd)***

I/O Standard	T_{IOPI}				T_{IOOP}				T_{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	1.0V			0.9V	1.0V			0.9V	1.0V			0.9V	
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	
DIFF_HSTL_II_DCI_F	0.75	0.79	0.92	0.76	0.97	1.08	1.15	1.30	1.61	1.84	1.97	1.91	ns
DIFF_HSTL_I_18_F	0.75	0.79	0.92	0.89	1.04	1.16	1.24	1.38	1.68	1.91	2.06	1.99	ns
DIFF_HSTL_II_18_F	0.75	0.79	0.92	0.89	0.98	1.09	1.16	1.40	1.62	1.85	1.98	2.01	ns
DIFF_HSTL_I_DCI_18_F	0.75	0.79	0.92	0.75	1.04	1.16	1.24	1.38	1.67	1.91	2.06	1.99	ns
DIFF_HSTL_II_DCI_18_F	0.75	0.79	0.92	0.75	0.98	1.09	1.16	1.33	1.61	1.85	1.98	1.94	ns
DIFF_HSTL_II _T_DCI_18_F	0.75	0.79	0.92	0.76	1.04	1.16	1.24	1.38	1.67	1.91	2.06	1.99	ns
LVCMOS18_S2	0.47	0.50	0.60	0.87	3.95	4.28	4.85	3.40	4.59	5.04	5.67	4.01	ns
LVCMOS18_S4	0.47	0.50	0.60	0.87	2.67	2.98	3.43	2.69	3.31	3.73	4.26	3.30	ns
LVCMOS18_S6	0.47	0.50	0.60	0.87	2.14	2.38	2.72	2.18	2.77	3.14	3.54	2.79	ns
LVCMOS18_S8	0.47	0.50	0.60	0.87	1.98	2.21	2.52	2.02	2.61	2.97	3.35	2.63	ns
LVCMOS18_S12	0.47	0.50	0.60	0.87	1.70	1.91	2.17	1.85	2.34	2.67	2.99	2.46	ns
LVCMOS18_S16	0.47	0.50	0.60	0.87	1.57	1.75	1.97	1.76	2.20	2.51	2.79	2.37	ns
LVCMOS18_F2	0.47	0.50	0.60	0.87	3.50	3.87	4.48	2.85	4.14	4.63	5.30	3.46	ns
LVCMOS18_F4	0.47	0.50	0.60	0.87	2.23	2.50	2.87	2.26	2.87	3.25	3.69	2.87	ns
LVCMOS18_F6	0.47	0.50	0.60	0.87	1.80	2.00	2.26	1.52	2.43	2.76	3.08	2.13	ns
LVCMOS18_F8	0.47	0.50	0.60	0.87	1.46	1.72	2.04	1.51	2.10	2.47	2.86	2.12	ns
LVCMOS18_F12	0.47	0.50	0.60	0.87	1.26	1.40	1.53	1.46	1.89	2.16	2.35	2.07	ns
LVCMOS18_F16	0.47	0.50	0.60	0.87	1.19	1.33	1.44	1.46	1.83	2.08	2.26	2.07	ns
LVCMOS15_S2	0.59	0.62	0.73	0.86	3.55	3.89	4.45	3.11	4.19	4.65	5.27	3.73	ns
LVCMOS15_S4	0.59	0.62	0.73	0.86	2.45	2.70	3.06	2.46	3.08	3.45	3.89	3.07	ns
LVCMOS15_S6	0.59	0.62	0.73	0.86	2.24	2.51	2.88	2.33	2.88	3.26	3.71	2.94	ns
LVCMOS15_S8	0.59	0.62	0.73	0.86	1.91	2.16	2.49	2.05	2.55	2.91	3.31	2.66	ns
LVCMOS15_S12	0.59	0.62	0.73	0.86	1.77	1.98	2.23	1.97	2.41	2.73	3.05	2.58	ns
LVCMOS15_S16	0.59	0.62	0.73	0.86	1.62	1.81	2.02	1.85	2.26	2.56	2.84	2.46	ns
LVCMOS15_F2	0.59	0.62	0.73	0.86	3.38	3.69	4.18	2.74	4.02	4.44	5.00	3.35	ns
LVCMOS15_F4	0.59	0.62	0.73	0.86	2.04	2.21	2.44	1.72	2.68	2.97	3.26	2.33	ns
LVCMOS15_F6	0.59	0.62	0.73	0.86	1.47	1.74	2.09	1.49	2.10	2.50	2.91	2.10	ns
LVCMOS15_F8	0.59	0.62	0.73	0.86	1.31	1.46	1.61	1.47	1.95	2.22	2.43	2.08	ns
LVCMOS15_F12	0.59	0.62	0.73	0.86	1.21	1.34	1.45	1.44	1.84	2.10	2.27	2.05	ns
LVCMOS15_F16	0.59	0.62	0.73	0.86	1.18	1.31	1.41	1.41	1.82	2.07	2.23	2.02	ns
LVCMOS12_S2	0.64	0.67	0.78	0.95	3.38	3.80	4.48	3.27	4.02	4.55	5.30	3.88	ns
LVCMOS12_S4	0.64	0.67	0.78	0.95	2.62	2.94	3.43	2.76	3.26	3.70	4.25	3.37	ns
LVCMOS12_S6	0.64	0.67	0.78	0.95	2.05	2.33	2.72	2.24	2.69	3.08	3.54	2.85	ns
LVCMOS12_S8	0.64	0.67	0.78	0.95	1.94	2.18	2.51	2.16	2.58	2.94	3.33	2.77	ns
LVCMOS12_F2	0.64	0.67	0.78	0.95	2.84	3.15	3.62	2.47	3.48	3.90	4.44	3.08	ns
LVCMOS12_F4	0.64	0.67	0.78	0.95	1.97	2.18	2.44	1.69	2.61	2.93	3.26	2.30	ns
LVCMOS12_F6	0.64	0.67	0.78	0.95	1.33	1.51	1.70	1.43	1.96	2.26	2.52	2.04	ns

Input/Output Logic Switching Characteristics

Table 22: **ILOGIC Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Setup/Hold						
T_{ICE1CK}/T_{ICKCE1}	CE1 pin Setup/Hold with respect to CLK	0.42/0.00	0.48/0.00	0.67/0.00	0.56/–0.16	ns
T_{ISRCK}/T_{ICKSR}	SR pin Setup/Hold with respect to CLK	0.53/0.01	0.61/0.01	0.99/0.01	0.88/–0.30	ns
$T_{IDOCKE2}/T_{IOCKDE2}$	D pin Setup/Hold with respect to CLK without Delay (HP I/O banks only)	0.01/0.27	0.01/0.29	0.01/0.34	0.01/0.41	ns
$T_{IDOCKDE2}/T_{IOCKDDE2}$	DDLY pin Setup/Hold with respect to CLK (using IDELAY) (HP I/O banks only)	0.01/0.27	0.02/0.29	0.02/0.34	0.01/0.41	ns
$T_{IDOCKE3}/T_{IOCKDE3}$	D pin Setup/Hold with respect to CLK without Delay (HR I/O banks only)	0.01/0.27	0.01/0.29	0.01/0.34	0.01/0.41	ns
$T_{IDOCKDE3}/T_{IOCKDDE3}$	DDLY pin Setup/Hold with respect to CLK (using IDELAY) (HR I/O banks only)	0.01/0.27	0.02/0.29	0.02/0.34	0.01/0.41	ns
Combinatorial						
T_{IDIE2}	D pin to O pin propagation delay, no Delay (HP I/O banks only)	0.09	0.10	0.12	0.14	ns
T_{IDIDE2}	DDLY pin to O pin propagation delay (using IDELAY) (HP I/O banks only)	0.10	0.11	0.13	0.15	ns
T_{IDIE3}	D pin to O pin propagation delay, no Delay (HR I/O banks only)	0.09	0.10	0.12	0.14	ns
T_{IDIDE3}	DDLY pin to O pin propagation delay (using IDELAY) (HR I/O banks only)	0.10	0.11	0.13	0.15	ns
Sequential Delays						
T_{IDLOE2}	D pin to Q1 pin using flip-flop as a latch without Delay (HP I/O banks only)	0.36	0.39	0.45	0.54	ns
$T_{IDLODE2}$	DDLY pin to Q1 pin using flip-flop as a latch (using IDELAY) (HP I/O banks only)	0.36	0.39	0.45	0.55	ns
T_{IDLOE3}	D pin to Q1 pin using flip-flop as a latch without Delay (HR I/O banks only)	0.36	0.39	0.45	0.54	ns
$T_{IDLODE3}$	DDLY pin to Q1 pin using flip-flop as a latch (using IDELAY) (HR I/O banks only)	0.36	0.39	0.45	0.55	ns
T_{ICKQ}	CLK to Q outputs	0.47	0.50	0.58	0.71	ns
$T_{RQ\_ILOGICE2}$	SR pin to OQ/TQ out (HP I/O banks only)	0.84	0.94	1.16	1.32	ns
$T_{GSRQ\_ILOGICE2}$	Global Set/Reset to Q outputs (HP I/O banks only)	7.60	7.60	10.51	11.39	ns
$T_{RQ\_ILOGICE3}$	SR pin to OQ/TQ out (HR I/O banks only)	0.84	0.94	1.16	1.32	ns
$T_{GSRQ\_ILOGICE3}$	Global Set/Reset to Q outputs (HR I/O banks only)	7.60	7.60	10.51	11.39	ns
Set/Reset						
$T_{RPW\_ILOGICE2}$	Minimum Pulse Width, SR inputs (HP I/O banks only)	0.54	0.63	0.63	0.68	ns, Min
$T_{RPW\_ILOGICE3}$	Minimum Pulse Width, SR inputs (HR I/O banks only)	0.54	0.63	0.63	0.68	ns, Min

Output Serializer/Deserializer Switching Characteristics

Table 25: **OSERDES Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Setup/Hold						
T_{OSDCK_D}/T_{OSCKD_D}	D input Setup/Hold with respect to CLKDIV	0.37/0.02	0.40/0.02	0.55/0.02	0.44/–0.24	ns
T_{OSDCK_T}/T_{OSCKD_T}(1)	T input Setup/Hold with respect to CLK	0.49/–0.15	0.56/–0.15	0.68/–0.15	0.67/–0.25	ns
$T_{OSDCK\_T2}/T_{OSCKD\_T2}$(1)	T input Setup/Hold with respect to CLKDIV	0.27/–0.15	0.30/–0.15	0.34/–0.15	0.46/–0.25	ns
$T_{OSCCK\_OCE}/T_{OSCKC\_OCE}$	OCE input Setup/Hold with respect to CLK	0.28/0.03	0.29/0.03	0.45/0.03	0.35/–0.15	ns
T_{OSCCK_S}	SR (Reset) input Setup with respect to CLKDIV	0.41	0.46	0.75	0.70	ns
$T_{OSCCK\_TCE}/T_{OSCKC\_TCE}$	TCE input Setup/Hold with respect to CLK	0.28/0.01	0.30/0.01	0.45/0.01	0.31/–0.15	ns
Sequential Delays						
T_{OSCKO_OQ}	Clock to out from CLK to OQ	0.35	0.37	0.42	0.54	ns
T_{OSCKO_TQ}	Clock to out from CLK to TQ	0.41	0.43	0.49	0.63	ns
Combinatorial						
T_{OSDO_TTQ}	T input to TQ Out	0.73	0.81	0.97	1.18	ns

Notes:

1. T_{OSDCK_T2} and T_{OSCKD_T2} are reported as T_{OSDCK_T}/T_{OSCKD_T} in TRACE report.

Input/Output Delay Switching Characteristics

Table 26: **Input/Output Delay Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
IDELAYCTRL						
T_{DLYCCO_RDY}	Reset to Ready for IDELAYCTRL	3.22	3.22	3.22	3.22	µs
$F_{IDELAYCTRL\_REF}$	Attribute REFCLK frequency = 200.00(1)	200.00	200.00	200.00	200.00	MHz
	Attribute REFCLK frequency = 300.00(1)	300.00	300.00	N/A	N/A	MHz
IDELAYCTRL_REF_PRECISION	REFCLK precision	±10	±10	±10	±10	MHz
$T_{IDELAYCTRL\_RPW}$	Minimum Reset pulse width	52.00	52.00	52.00	52.00	ns
IDELAY/ODELAY						
$T_{IDELAYRESOLUTION}$	IDELAY/ODELAY chain delay resolution	1/(32 x 2 x F_{REF})				ps
$T_{IDELAYPAT\_JIT}$ and $T_{ODELAYPAT\_JIT}$	Pattern dependent period jitter in delay chain for clock pattern.(2)	0	0	0	0	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23)(3)	±5	±5	±5	±5	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23)(4)	±9	±9	±9	±9	ps per tap
$T_{IDELAY\_CLK\_MAX}$/ $T_{ODELAY\_CLK\_MAX}$	Maximum frequency of CLK input to IDELAY/ODELAY	800.00	800.00	710.00	710.00	MHz
T_{IDCCK_CE} / T_{IDCKC_CE}	CE pin Setup/Hold with respect to C for IDELAY	0.11/0.10	0.14/0.12	0.18/0.14	0.14/0.16	ns
T_{ODCCK_CE} / T_{ODCKC_CE}	CE pin Setup/Hold with respect to C for ODELAY	0.14/0.03	0.16/0.04	0.19/0.05	0.28/0.06	ns
T_{IDCCK_INC}/ T_{IDCKC_INC}	INC pin Setup/Hold with respect to C for IDELAY	0.10/0.14	0.12/0.16	0.14/0.20	0.10/0.23	ns
T_{ODCCK_INC}/ T_{ODCKC_INC}	INC pin Setup/Hold with respect to C for ODELAY	0.10/0.07	0.12/0.08	0.13/0.09	0.19/0.16	ns
T_{IDCCK_RST}/ T_{IDCKC_RST}	RST pin Setup/Hold with respect to C for IDELAY	0.13/0.08	0.14/0.10	0.16/0.12	0.22/0.19	ns
T_{ODCCK_RST}/ T_{ODCKC_RST}	RST pin Setup/Hold with respect to C for ODELAY	0.16/0.04	0.19/0.06	0.24/0.08	0.32/0.11	ns
$T_{IDDO\_IDATAIN}$	Propagation delay through IDELAY	Note 5	Note 5	Note 5	Note 5	ps
$T_{ODDO\_ODATAIN}$	Propagation delay through ODELAY	Note 5	Note 5	Note 5	Note 5	ps

Notes:

1. Average Tap Delay at 200 MHz = 78 ps, at 300 MHz = 52 ps.
2. When HIGH_PERFORMANCE mode is set to TRUE or FALSE.
3. When HIGH_PERFORMANCE mode is set to TRUE.
4. When HIGH_PERFORMANCE mode is set to FALSE.
5. Delay depends on IDELAY/ODELAY tap setting. See TRACE report for actual values.

Table 27: **IO_FIFO Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
IO_FIFO Clock to Out Delays						
T_{OFFCKO_DO}	RDCLK to Q outputs	0.51	0.56	0.63	0.81	ns
T_{CKO_FLAGS}	Clock to IO_FIFO Flags	0.59	0.62	0.81	0.77	ns
Setup/Hold						
T_{CCK_D}/T_{CKC_D}	D inputs to WRCLK	0.43/–0.01	0.47/–0.01	0.53/–0.01	0.76/–0.05	ns
$T_{IFFCCK\_WREN}/T_{IFFCKC\_WREN}$	WREN to WRCLK	0.39/–0.01	0.43/–0.01	0.50/–0.01	0.70/–0.05	ns
$T_{OFFCCK\_RDEN}/T_{OFFCKC\_RDEN}$	RDEN to RDCLK	0.49/0.01	0.53/0.02	0.61/0.02	0.79/–0.02	ns
Minimum Pulse Width						
$T_{PWH\_IO\_FIFO}$	RESET, RDCLK, WRCLK	0.81	0.92	1.08	1.29	ns
$T_{PWL\_IO\_FIFO}$	RESET, RDCLK, WRCLK	0.81	0.92	1.08	1.29	ns
Maximum Frequency						
F_{MAX}	RDCLK and WRCLK	533.05	470.37	400.00	333.33	MHz

CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 29: **CLB Distributed RAM Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Sequential Delays						
T_{SHCKO}	Clock to A – B outputs	0.68	0.70	0.85	1.08	ns, Max
T_{SHCKO_1}	Clock to AMUX – BMUX outputs	0.91	0.95	1.15	1.44	ns, Max
Setup and Hold Times Before/After Clock CLK						
T_{DS_LRAM}/T_{DH_LRAM}	A – D inputs to CLK	0.45/0.23	0.45/0.24	0.54/0.27	0.69/0.33	ns, Min
T_{AS_LRAM}/T_{AH_LRAM}	Address An inputs to clock	0.13/0.50	0.14/0.50	0.17/0.58	0.21/0.63	ns, Min
	Address An inputs through MUXs and/or carry logic to clock	0.40/0.16	0.42/0.17	0.52/0.23	0.63/0.23	ns, Min
T_{WS_LRAM}/T_{WH_LRAM}	WE input to clock	0.29/0.09	0.30/0.09	0.36/0.09	0.46/0.10	ns, Min
T_{CECK_LRAM}/ T_{CKCE_LRAM}	CE input to CLK	0.29/0.09	0.30/0.09	0.37/0.09	0.47/0.10	ns, Min
Clock CLK						
T_{MPW}	Minimum pulse width	0.68	0.77	0.91	1.11	ns, Min
T_{MCP}	Minimum clock period	1.35	1.54	1.82	2.22	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time.
2. T_{SHCKO} also represents the CLK to XMUX output. Refer to TRACE report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 30: **CLB Shift Register Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Sequential Delays						
T_{REG}	Clock to A – D outputs	0.96	0.98	1.20	1.35	ns, Max
T_{REG_MUX}	Clock to AMUX – DMUX output	1.19	1.23	1.50	1.72	ns, Max
T_{REG_M31}	Clock to DMUX output via M31 output	0.89	0.91	1.10	1.25	ns, Max
Setup and Hold Times Before/After Clock CLK						
T_{WS_SHFREG}/ T_{WH_SHFREG}	WE input	0.26/0.09	0.27/0.09	0.33/0.09	0.41/0.10	ns, Min
T_{CECK_SHFREG}/ T_{CKCE_SHFREG}	CE input to CLK	0.27/0.09	0.28/0.09	0.33/0.09	0.42/0.10	ns, Min
T_{DS_SHFREG}/ T_{DH_SHFREG}	A – D inputs to CLK	0.28/0.26	0.28/0.26	0.33/0.30	0.41/0.36	ns, Min
Clock CLK						
T_{MPW_SHFREG}	Minimum pulse width	0.55	0.65	0.78	0.91	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time.

Block RAM and FIFO Switching Characteristics

Table 31: **Block RAM and FIFO Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Block RAM and FIFO Clock-to-Out Delays						
T_{RCKO_DO} and $T_{RCKO\_DO\_REG}$[1]	Clock CLK to DOUT output (without output register)[2][3]	1.57	1.80	2.08	2.44	ns, Max
	Clock CLK to DOUT output (with output register)[4][5]	0.54	0.63	0.75	0.86	ns, Max
$T_{RCKO\_DO\_ECC}$ and $T_{RCKO\_DO\_ECC\_REG}$	Clock CLK to DOUT output with ECC (without output register)[2][3]	2.35	2.58	3.26	4.49	ns, Max
	Clock CLK to DOUT output with ECC (with output register)[4][5]	0.62	0.69	0.80	0.94	ns, Max
$T_{RCKO\_DO\_CASCOUT}$ and $T_{RCKO\_DO\_CASCOUT\_REG}$	Clock CLK to DOUT output with Cascade (without output register)[2]	2.21	2.45	2.80	3.19	ns, Max
	Clock CLK to DOUT output with Cascade (with output register)[4]	0.98	1.08	1.24	1.32	ns, Max
T_{RCKO_FLAGS}	Clock CLK to FIFO flags outputs[6]	0.65	0.74	0.89	0.97	ns, Max
$T_{RCKO\_POINTERS}$	Clock CLK to FIFO pointers outputs[7]	0.79	0.87	0.98	1.10	ns, Max
$T_{RCKO\_PARITY\_ECC}$	Clock CLK to ECCPARITY in ECC encode only mode	0.66	0.72	0.80	0.93	ns, Max
$T_{RCKO\_SDBIT\_ECC}$ and $T_{RCKO\_SDBIT\_ECC\_REG}$	Clock CLK to BITERR (without output register)	2.17	2.38	3.01	4.15	ns, Max
	Clock CLK to BITERR (with output register)	0.57	0.65	0.76	0.89	ns, Max
$T_{RCKO\_RDADDR\_ECC}$ and $T_{RCKO\_RDADDR\_ECC\_REG}$	Clock CLK to RDADDR output with ECC (without output register)	0.64	0.74	0.90	0.98	ns, Max
	Clock CLK to RDADDR output with ECC (with output register)	0.71	0.79	0.92	1.10	ns, Max
Setup and Hold Times Before/After Clock CLK						
$T_{RCCK\_ADDRA}/T_{RCKC\_ADDRA}$	ADDR inputs[8]	0.38/0.27	0.42/0.28	0.48/0.31	0.65/0.38	ns, Min
$T_{RDCK\_DI\_WF\_NC}/T_{RCKD\_DI\_WF\_NC}$	Data input setup/hold time when block RAM is configured in WRITE_FIRST or NO_CHANGE mode[9]	0.49/0.51	0.55/0.53	0.63/0.57	0.78/0.64	ns, Min
$T_{RDCK\_DI\_RF}/T_{RCKD\_DI\_RF}$	Data input setup/hold time when block RAM is configured in READ_FIRST mode[9]	0.17/0.25	0.19/0.29	0.21/0.35	0.25/0.32	ns, Min
$T_{RDCK\_DI\_ECC}/T_{RCKD\_DI\_ECC}$	DIN inputs with block RAM ECC in standard mode[9]	0.42/0.37	0.47/0.39	0.53/0.43	0.66/0.46	ns, Min
$T_{RDCK\_DI\_ECCW}/T_{RCKD\_DI\_ECCW}$	DIN inputs with block RAM ECC encode only[9]	0.79/0.37	0.87/0.39	0.99/0.43	1.17/0.41	ns, Min
$T_{RDCK\_DI\_ECC\_FIFO}/T_{RCKD\_DI\_ECC\_FIFO}$	DIN inputs with FIFO ECC in standard mode[9]	0.89/0.47	0.98/0.50	1.12/0.54	1.32/0.65	ns, Min
$T_{RCCK\_INJECTBITERR}/T_{RCKC\_INJECTBITERR}$	Inject single/double bit error in ECC mode	0.49/0.30	0.55/0.31	0.63/0.34	0.78/0.41	ns, Min
T_{RCCK_EN}/T_{RCKC_EN}	Block RAM Enable (EN) input	0.30/0.17	0.33/0.18	0.38/0.20	0.48/0.22	ns, Min
$T_{RCCK\_REGCE}/T_{RCKC\_REGCE}$	CE input of output register	0.21/0.13	0.25/0.13	0.31/0.14	0.34/0.16	ns, Min
$T_{RCCK\_RSTREG}/T_{RCKC\_RSTREG}$	Synchronous RSTREG input	0.25/0.06	0.27/0.06	0.29/0.06	0.35/0.06	ns, Min

Table 39: **PLL Specification *(Cont'd)***

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
PLL_F_{PFDMAX}	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized	550.00	500.00	450.00	450.00	MHz
	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	300.00	300.00	300.00	300.00	MHz
PLL_F_{PFDMIN}	Minimum Frequency at the Phase Frequency Detector	19.00	19.00	19.00	19.00	MHz
PLL_$T_{FBDELAY}$	Maximum Delay in the Feedback Path	3 ns Max or one CLKIN cycle				
Dynamic Reconfiguration Port (DRP) for PLL Before and After DCLK						
T_{PLLCCK_DADDR}/ T_{PLLCKC_DADDR}	Setup and hold of D address	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_{PLLCCK_DI}/ T_{PLLCKC_DI}	Setup and hold of D input	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_{PLLCCK_DEN}/ T_{PLLCKC_DEN}	Setup and hold of D enable	1.76/0.00	1.97/0.00	2.29/0.00	2.40/0.00	ns, Min
T_{PLLCCK_DWE}/ T_{PLLCKC_DWE}	Setup and hold of D write enable	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_{PLLCKO_DRDY}	CLK to out of DRDY	0.65	0.72	0.99	0.70	ns, Max
F_{DCK}	DCLK frequency	200.00	200.00	200.00	100.00	MHz, Max

Notes:

1. The PLL does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
2. The static offset is measured between any PLL outputs with identical phase.
3. Values for this parameter are available in the Clocking Wizard. See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
4. Includes global clock buffer.
5. Calculated as F_{VCO}/128 assuming output duty cycle is 50%.

Table 42: **Clock-Capable Clock Input to Output Delay With MMCM**

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, *with* MMCM.							
$T_{ICKOFMMCMCC}$	Clock-capable clock input and OUTFF *with* MMCM	XC7K70T	0.95	0.95	0.95	1.74	ns
		XC7K160T	0.96	0.96	0.96	1.78	ns
		XC7K325T	1.00	1.00	1.00	1.82	ns
		XC7K355T	1.00	1.00	1.00	1.78	ns
		XC7K410T	1.00	1.00	1.00	1.82	ns
		XC7K420T	1.07	1.07	1.07	1.82	ns
		XC7K480T	1.07	1.07	1.07	1.82	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

Table 43: **Clock-Capable Clock Input to Output Delay With PLL**

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, *with* PLL.							
$T_{ICKOFPLLCC}$	Clock-capable clock input and OUTFF *with* PLL	XC7K70T	0.84	0.84	0.84	1.45	ns
		XC7K160T	0.89	0.89	0.89	1.54	ns
		XC7K325T	0.89	0.89	0.89	1.54	ns
		XC7K355T	0.89	0.89	0.89	1.50	ns
		XC7K410T	0.89	0.89	0.89	1.54	ns
		XC7K420T	0.96	0.96	0.96	1.54	ns
		XC7K480T	0.96	0.96	0.96	1.54	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. PLL output jitter is already included in the timing calculation.

Table 44: **Pin-to-Pin, Clock-to-Out using BUFIO**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, *with* BUFIO.						
$T_{ICKOFCS}$	Clock-to-Out of I/O clock for HR I/O banks	4.93	5.52	6.20	6.97	ns
	Clock-to-Out of I/O clock for HP I/O banks	4.85	5.44	6.11	6.90	ns

Table 47: **Clock-Capable Clock Input Setup and Hold With PLL**

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to Clock-Capable Clock Input Signal for SSTL15 Standard.(1)							
$T_{PSPLLCC}$/ $T_{PHPLLCC}$	No Delay clock-capable clock input and IFF(2) with PLL	XC7K70T	2.75/–0.32	3.04/–0.32	3.33/–0.32	2.42/–0.54	ns
		XC7K160T	2.85/–0.31	3.16/–0.31	3.46/–0.31	2.59/–0.56	ns
		XC7K325T	2.91/–0.27	3.24/–0.27	3.54/–0.27	2.80/–0.56	ns
		XC7K355T	2.79/–0.27	3.12/–0.27	3.40/–0.27	2.67/–0.52	ns
		XC7K410T	2.91/–0.27	3.24/–0.27	3.53/–0.27	2.78/–0.56	ns
		XC7K420T	2.83/–0.20	3.12/–0.20	3.41/–0.20	2.61/–0.50	ns
		XC7K480T	2.83/–0.20	3.12/–0.20	3.41/–0.20	2.61/–0.50	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 48: **Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to a Forwarded Clock Input Pin Using BUFIO for SSTL15 Standard.						
T_{PSCS}/T_{PHCS}	Setup/Hold of I/O clock for HR I/O banks	–0.36/1.36	–0.36/1.50	–0.36/1.70	–0.44/1.87	ns
	Setup/Hold of I/O clock for HP I/O banks	–0.34/1.39	–0.34/1.53	–0.34/1.73	–0.44/1.87	ns

Table 49: **Sample Window**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
T_{SAMP}	Sampling Error at Receiver Pins(1)	0.51	0.56	0.61	0.56	ns
T_{SAMP_BUFIO}	Sampling Error at Receiver Pins using BUFIO(2)	0.30	0.35	0.40	0.35	ns

Notes:

1. This parameter indicates the total sampling error of the Kintex-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
   - CLK0 MMCM jitter
   - MMCM accuracy (phase offset)
   - MMCM phase shift resolution

   These measurements do not include package or clock tree skew.
2. This parameter indicates the total sampling error of the Kintex-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIO clock network and IDELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

GTX Transceiver Specifications

GTX Transceiver DC Input and Output Levels

Table 51 summarizes the DC output specifications of the GTX transceivers in Kintex-7 FPGAs. Consult UG476: *7 Series FPGAs GTX/GTH Transceiver User Guide* for further details.

Table 51: **GTX Transceiver DC Specifications**

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV_{PPOUT}	Differential peak-to-peak output voltage(1)	Transmitter output swing is set to maximum setting	–	–	1000	mV
$V_{CMOUTDC}$	DC common mode output voltage.	Equation based	$V_{MGTAVTT} - DV_{PPOUT}/4$			mV
R_{OUT}	Differential output resistance		–	100	–	Ω
T_{OSKEW}	Transmitter output pair (TXP and TXN) intra-pair skew		–	2	12	ps
DV_{PPIN}	Differential peak-to-peak input voltage (external AC coupled)	>10.3125 Gb/s	150	–	1250	mV
		6.6 Gb/s to 10.3125 Gb/s	150	–	1250	mV
		≤ 6.6 Gb/s	150	–	2000	mV
V_{IN}	Absolute input voltage	DC coupled $V_{MGTAVTT}$ = 1.2V	–200	–	$V_{MGTAVTT}$	mV
V_{CMIN}	Common mode input voltage	DC coupled $V_{MGTAVTT}$ = 1.2V	–	2/3 $V_{MGTAVTT}$	–	mV
R_{IN}	Differential input resistance		–	100	–	Ω
C_{EXT}	Recommended external AC coupling capacitor(2)		–	100	–	nF

Notes:

1. The output swing and preemphasis levels are programmable using the attributes discussed in UG476: *7 Series FPGAs GTX/GTH Transceiver User Guide* and can result in values lower than reported in this table.
2. Other values can be used as appropriate to conform to specific protocols and standards.

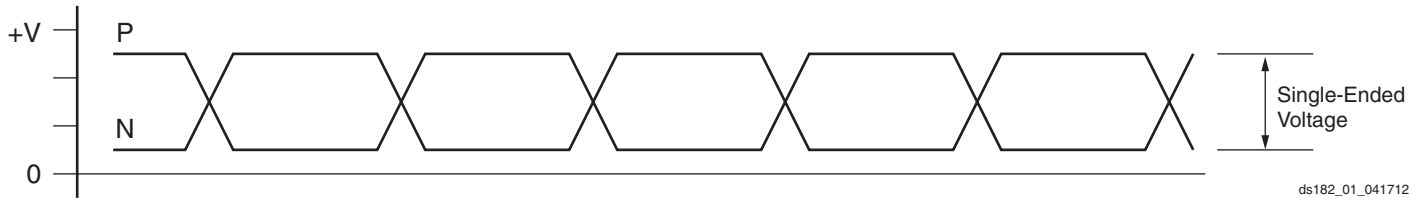

Figure 1: **Single-Ended Peak-to-Peak Voltage**

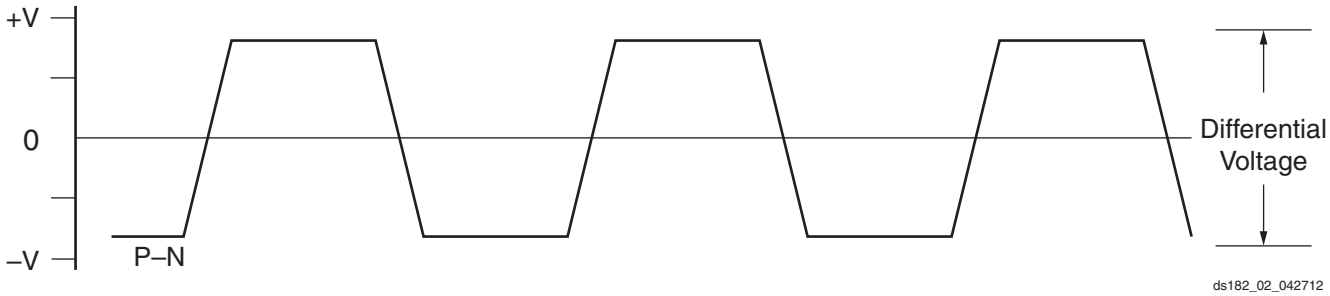

Figure 2: **Differential Peak-to-Peak Voltage**

Table 53: **GTX Transceiver Performance *(Cont'd)***

Symbol	Description	Output Divider	Speed Grade								Units
			1.0V						0.9V		
			-3		-2/-2L		-1[1]		-2L[2]		
			Package Type								
			FF	FB	FF	FB	FF	FB	FF	FB	
$F_{GQPLLRANGE2}$	GTX transceiver QPLL frequency range 2		9.8–12.5		9.8–10.3125		N/A		N/A		GHz

Notes:

1. The -1 speed grade requires a 4-byte internal data width for operation above 5.0 Gb/s.
2. The -2L (0.9V) speed grade requires a 4-byte internal data width for operation above 3.8 Gb/s.
3. Data rates between 8.0 Gb/s and 9.8 Gb/s are not available.
4. For QPLL line rate range 2, the maximum line rate with the divider N set to 66 is 10.3125Gb/s.

Table 54: **GTX Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
$F_{GTXDRPCLK}$	GTXDRPCLK maximum frequency	175.01	175.01	156.25	125.00	MHz

Table 55: **GTX Transceiver Reference Clock Switching Characteristics**

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range	-3 speed grade	60	–	700	MHz
		All other speed grades	60	–	670	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	–	200	–	ps
T_{FCLK}	Reference clock fall time	80% – 20%	–	200	–	ps
T_{DCREF}	Reference clock duty cycle	Transceiver PLL only	40	50	60	%

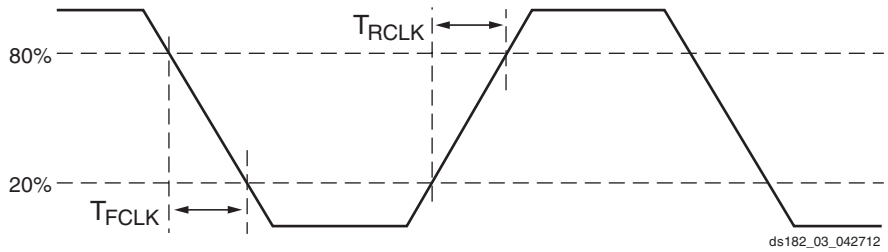

Figure 3: **Reference Clock Timing Parameters**

Table 56: **GTX Transceiver PLL /Lock Time Adaptation**

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
T_{LOCK}	Initial PLL lock		–	–	1	ms
T_{DLOCK}	Clock recovery phase acquisition and adaptation time for decision feedback equalizer (DFE).	After the PLL is locked to the reference clock, this is the time it takes to lock the clock data recovery (CDR) to the data present at the input.	–	50,000	37 x10^6	UI
	Clock recovery phase acquisition and adaptation time for low-power mode (LPM) when the DFE is disabled.		–	50,000	2.3 x10^6	UI

Table 57: **GTX Transceiver User Clock Switching Characteristics(1)(2)**

Symbol	Description	Conditions	Speed Grade				Units
			1.0V			0.9V	
			-3(3)	-2/-2L(3)	-1(4)	-2L(5)	
F_{TXOUT}	TXOUTCLK maximum frequency		412.54	412.54	312.50	237.53	MHz
F_{RXOUT}	RXOUTCLK maximum frequency		412.54	412.54	312.50	237.53	MHz
F_{TXIN}	TXUSRCLK maximum frequency	16-bit data path	412.54	412.54	312.50	237.53	MHz
		32-bit data path	391.08	322.37	250.00	206.27	MHz
F_{RXIN}	RXUSRCLK maximum frequency	16-bit data path	412.54	412.54	312.50	237.53	MHz
		32-bit data path	391.08	322.37	250.00	206.27	MHz
F_{TXIN2}	TXUSRCLK2 maximum frequency	16-bit data path	412.54	412.54	312.50	237.53	MHz
		32-bit data path	391.08	322.37	250.00	206.27	MHz
		64-bit data path	195.54	161.19	125.00	103.14	MHz
F_{RXIN2}	RXUSRCLK2 maximum frequency	16-bit data path	412.54	412.54	312.50	237.53	MHz
		32-bit data path	391.08	322.37	250.00	206.27	MHz
		64-bit data path	195.54	161.19	125.00	103.14	MHz

Notes:

1. Clocking must be implemented as described in UG476: *7 Series FPGAs GTX/GTH Transceiver User Guide*.
2. These frequencies are not supported for all possible transceiver configurations.
3. For speed grades -3, -2, -2L (1.0V), a 16-bit data path can only be used for speeds less than 6.6 Gb/s.
4. For speed grade -1, a 16-bit data path can only be used for speeds less than 5.0 Gb/s.
5. For speed grade -2L (0.9V), a 16-bit data path can only be used for speeds less than 3.8 Gb/s.

Table 58: **GTX Transceiver Transmitter Switching Characteristics**

Symbol	Description	Condition	Min	Typ	Max	Units
F_{GTXTX}	Serial data rate range		0.500	–	F_{GTXMAX}	Gb/s
T_{RTX}	TX Rise time	20%–80%	–	40	–	ps
T_{FTX}	TX Fall time	80%–20%	–	40	–	ps
T_{LLSKEW}	TX lane-to-lane skew(1)		–	–	500	ps
$V_{TXOOBVDPP}$	Electrical idle amplitude		–	–	15	mV
$T_{TXOOBTRANSITION}$	Electrical idle transition time		–	–	140	ns
$TJ_{12.5}$	Total Jitter(2)(4)	12.5 Gb/s	–	–	0.28	UI
$DJ_{12.5}$	Deterministic Jitter(2)(4)		–	–	0.17	UI
$TJ_{11.18}$	Total Jitter(2)(4)	11.18 Gb/s	–	–	0.28	UI
$DJ_{11.18}$	Deterministic Jitter(2)(4)		–	–	0.17	UI

GTX Transceiver Protocol Jitter Characteristics

For Table 60 through Table 65, the UG476: *7 Series FPGAs GTX/GTH Transceiver User Guide* contains recommended settings for optimal usage of protocol specific characteristics.

Table 60: **Gigabit Ethernet Protocol Characteristics**

Description	Line Rate (Mb/s)	Min	Max	Units
Gigabit Ethernet Transmitter Jitter Generation				
Total transmitter jitter (T_TJ)	1250	–	0.24	UI
Gigabit Ethernet Receiver High Frequency Jitter Tolerance				
Total receiver jitter tolerance	1250	0.749	–	UI

Table 61: **XAUI Protocol Characteristics**

Description	Line Rate (Mb/s)	Min	Max	Units
XAUI Transmitter Jitter Generation				
Total transmitter jitter (T_TJ)	3125	–	0.35	UI
XAUI Receiver High Frequency Jitter Tolerance				
Total receiver jitter tolerance	3125	0.65	–	UI

Table 62: **PCI Express Protocol Characteristics(1)**

Standard	Description		Line Rate (Mb/s)	Min	Max	Units
PCI Express Transmitter Jitter Generation						
PCI Express Gen 1	Total transmitter jitter		2500	–	0.25	UI
PCI Express Gen 2	Total transmitter jitter		5000	–	0.25	UI
PCI Express Gen 3(2)	Total transmitter jitter uncorrelated		8000	–	31.25	ps
	Deterministic transmitter jitter uncorrelated			–	12	ps
PCI Express Receiver High Frequency Jitter Tolerance						
PCI Express Gen 1	Total receiver jitter tolerance		2500	0.65	–	UI
PCI Express Gen 2(3)	Receiver inherent timing error		5000	0.40	–	UI
	Receiver inherent deterministic timing error			0.30	–	UI
PCI Express Gen 3(2)	Receiver sinusoidal jitter tolerance	0.03 MHz–1.0 MHz	8000	1.00	–	UI
		1.0 MHz–10 MHz		Note 4	–	UI
		10 MHz–100 MHz		0.10	–	UI

Notes:

1. Tested per card electromechanical (CEM) methodology.
2. PCI-SIG 3.0 certification and compliance test boards are currently not available.
3. Using common REFCLK.
4. Between 1 MHz and 10 MHz the minimum sinusoidal jitter roll-off with a slope of 20dB/decade.

Table 67: **XADC Specifications *(Cont'd)***

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
XADC Reference[5]						
External Reference	V_{REFP}	Externally supplied reference voltage	1.20	1.25	1.30	V
On-Chip Reference		Ground V_{REFP} pin to AGND, T_j = –40°C to 100°C	1.2375	1.25	1.2625	V

Notes:

1. Offset and gain errors are removed by enabling the XADC automatic gain calibration feature. The values are specified for when this feature is enabled.
2. Only specified for new BitGen option XADCEnhancedLinearity = ON.
3. See the ADC chapter in UG480: *7 Series FPGAs XADC User Guide* for a detailed description.
4. See the Timing chapter in UG480: *7 Series FPGAs XADC User Guide* for a detailed description.
5. Any variation in the reference voltage from the nominal V_{REFP} = 1.25V and V_{REFN} = 0V will result in a deviation from the ideal transfer function. This also impacts the accuracy of the internal sensor measurements (i.e., temperature and power supply). However, for external ratiometric type applications allowing reference to vary by ±4% is permitted. On-chip reference variation is ±1%.

Configuration Switching Characteristics

Table 68: **Configuration Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Power-up Timing Characteristics						
T_{PL}[1]	Program latency	5	5	5	5	ms, Max
T_{POR}[1]	Power-on reset (50 ms ramp rate time)	10/50	10/50	10/50	10/50	ms, Min/Max
	Power-on reset (1 ms ramp rate time)	10/35	10/35	10/35	10/35	ms, Min/Max
$T_{PROGRAM}$	Program pulse width	250	250	250	250	ns, Min
CCLK Output (Master Mode)						
T_{ICCK}	Master CCLK output delay	150	150	150	150	ns, Min
T_{MCCKL}	Master CCLK clock Low time duty cycle	40/60	40/60	40/60	40/60	%, Min/Max
T_{MCCKH}	Master CCLK clock High time duty cycle	40/60	40/60	40/60	40/60	%, Min/Max
F_{MCCK}	Master CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max
	Master CCLK frequency for AES encrypted x16	50.00	50.00	50.00	35.00	MHz, Max
F_{MCCK_START}	Master CCLK frequency at start of configuration	3.00	3.00	3.00	3.00	MHz, Typ
$F_{MCCKTOL}$	Frequency tolerance, master mode with respect to nominal CCLK	±50	±50	±50	±50	%, Max
CCLK Input (Slave Modes)						
T_{SCCKL}	Slave CCLK clock minimum Low time	2.50	2.50	2.50	2.50	ns, Min
T_{SCCKH}	Slave CCLK clock minimum High time	2.50	2.50	2.50	2.50	ns, Min
F_{SCCK}	Slave CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max
EMCCLK Input (Master Mode)						
T_{EMCCKL}	External master CCLK Low time	2.50	2.50	2.50	2.50	ns, Min
T_{EMCCKH}	External master CCLK High time	2.50	2.50	2.50	2.50	ns, Min
F_{EMCCK}	External master CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max
Internal Configuration Access Port						
F_{ICAPCK}	Internal configuration access port (ICAPE2)	100.00	100.00	100.00	70.00	MHz, Max

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